

Notice of References Cited			Application/Control No.	Applicant(s)/Patent Under Reexamination IWASAKI ET AL.	
			10/765,281	Examiner John D. Lee <i>John D. Lee</i>	Art Unit 2874

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,993,020	11-1999	Koike, Yasuhiro	362/628
*	B	US-6,412,968	07-2002	Ohkawa, Shingo	362/26
*	C	US-6,907,177	06-2005	Iwasaki et al.	385/129
*	D	US-2005/0162863	07-2005	Iwasaki, Osamu	362/551
*	E	US-2005/0163422	07-2005	Iwasaki, Osamu	385/024
*	F	US-2005/0163442	07-2005	Iwasaki, Osamu	385/123
*	G	US-2005/0163454	07-2005	Iwasaki et al.	385/146
*	H	US-2005/0201706	09-2005	Iwasaki, Osamu	385/129
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.